

Search Notes**Application/Control No.**

10/572,961

Examiner

CHRIS C. CHU

**Applicant(s)/Patent under
Reexamination**

FUKUDA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E23.188, E23.009, 712 & 703	7/4/2008	C.C.
257	706 & 750	7/4/2008	C.C.
428	469 & 698	7/4/2008	C.C.
428	209 & 210	7/4/2008	C.C.
361	704	7/4/2008	C.C.
228	121	7/4/2008	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	7/4/2008	C.C.